



PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicants: Young Hoon Kwark

Examiner: Emily Y. Chan

Serial No: 10/769,115

Group Art Unit: 2829

Filed: January 30, 2004

Docket: YOR20030625US1 (163-27)

For: CONTACTLESS CIRCUIT TESTING FOR ADAPTIVE WAFER PROCESSING

Mail Stop AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**AMENDMENT UNDER 37 C.F.R. §1.116**

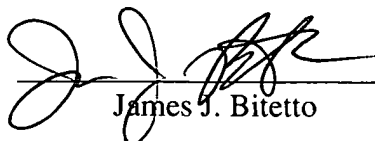
Sir:

This is a response to the Office Action mailed December 23, 2005. Please amend the above-identified application as follows:

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**CERTIFICATE OF MAILING 37 C.F.R. §1.8(a)**

I hereby certify that this correspondence (and any document referred to as being attached or enclosed) is being deposited with the United States Postal Service as first class mail, postage paid in an envelope addressed to: Mail Stop AF, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450 on 3/21/06.

  
James J. Bitetto